



# Test Report

Report No: KEYS24050817002RH-03

Date: May 16, 2024

Page 1 of 4

**Applicant** : Shenzhen Slkormicro Semicon Co., Ltd.  
**Address** : 2010, Block A, Bairuida Building Vanke City Community Bantian Avenue,  
Longgang District, Shenzhen, Guangdong, China.  
**Manufacturer** : Shenzhen Slkormicro Semicon Co., Ltd.  
**Address** : 2010, Block A, Bairuida Building Vanke City Community Bantian Avenue,  
Longgang District, Shenzhen, Guangdong, China.

The following sample(s) was /were submitted and identified on behalf of the clients as:

**Trade Mark** : Slkor

**Sample Name** : Semiconductor power devices

**Sample Model** : SL78L05, SOT-89, SOT-223 SOD-323, SOD-523, SOT-323, SOT-523,  
SOT-723, SOD-323F, SOT-363, SOD-123 SOD-123FL, SOT-553, SMA,  
SMB, SMC, SMAF, SMBF, TO-277, SOT143, SOT-343R SOT-143B,  
SOT-143R, TO-252, SOT-23-3L, SOT-23-5, SOT-23-6, SOT-23-8, TO-263  
TO-264, TO-220, TO-220F, TO-3P, TO-263-5, TO-252-4, TO-252-5, SOP-8,  
DFN1006, 0603, 3528, SOD-123W, TO-3PF, TO-3PH, SSOP-4, SSOP-10,  
SOD-882, SOD-923, SOP-5, QFN32, ESOP-8, MSOP-8, TO-251, TO-247,  
TO-247-2, TO-247-3, TO-247-4 SOP-20, SSOP-16, DFN1610, PDFN, TO-92,  
TO-92S, DIP-16, DIP-8, DIP-4, DIP-6, DIP-18 SOP-16 SOP16W SOP-14  
DIP-14, ABS, MBF, MBS, GBP, KBP, GBU, KBLDBS, DFS, SOIC-8L,  
UMSB, SMD-4, SMD-6, SMD-8, DFN2510, DFN2020-3L, DFN1006-2L  
DFN1006-3L PDFN5\*6 PDFN5\*6-8L DFNO603 PDFN3\*3-8L TO-126  
DFN2x2-6L DFN1610-6L, PDFN3.3\*3.3, QFN3\*3, DFN5\*6

**Sample Received Date** : May 11, 2024

**Testing Period** : May 12, 2024 To May 16, 2024

**Test Requested** : Total Lead (Pb), Cadmium(Cd), Phthalates(7P) content according to California  
Proposition 65

**Test Method** : Please refer to next page(s).

**Test Result** : Please refer to next page(s).

**Conclusion** : **PASS** (Based on test results)

Signed for and on behalf of

Tony Qian/ Technical Director

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Guangdong KEYS Testing Technology Co., Ltd.

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Page 2 of 4

## Sample Description:

No.	Name
1	Triode

## Test method and Test equipment:

Test Item	Test Method	Test Equipment
Lead(Pb)	IEC 62321-5:2013	ICP-AES
Cadmium(Cd)	IEC 62321-5:2013	ICP-AES
Phthalate	CPSC-CH-C1001-09.4	GC-MS

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Page 3 of 4

## Test Result :

Test Item(s)	Unit	Result					MDL	Limit
		No.1	--	--	--	--		
Cadmium(Cd)	mg/kg	N.D.	--	--	--	--	2	300
Lead(Pb)	mg/kg	N.D.	--	--	--	--	2	100
Dibutyl Phthalate(DBP)	mg/kg	--	--	--	--	--	30	1000
Di-(2-ethylhexyl) Phthalate (DEHP)	mg/kg	--	--	--	--	--	30	1000
Benzylbutyl Phthalate(BBP)	mg/kg	--	--	--	--	--	30	1000
Diisononyl Phthalate (DINP)	mg/kg	--	--	--	--	--	50	1000
Di-n-octyl Phthalate(DNOP)	mg/kg	--	--	--	--	--	30	1000
Diisodecyl Phthalate (DIDP)	mg/kg	--	--	--	--	--	50	1000
Di-n-hexyl- phthalate(DnHP)	mg/kg	--	--	--	--	--	50	1000

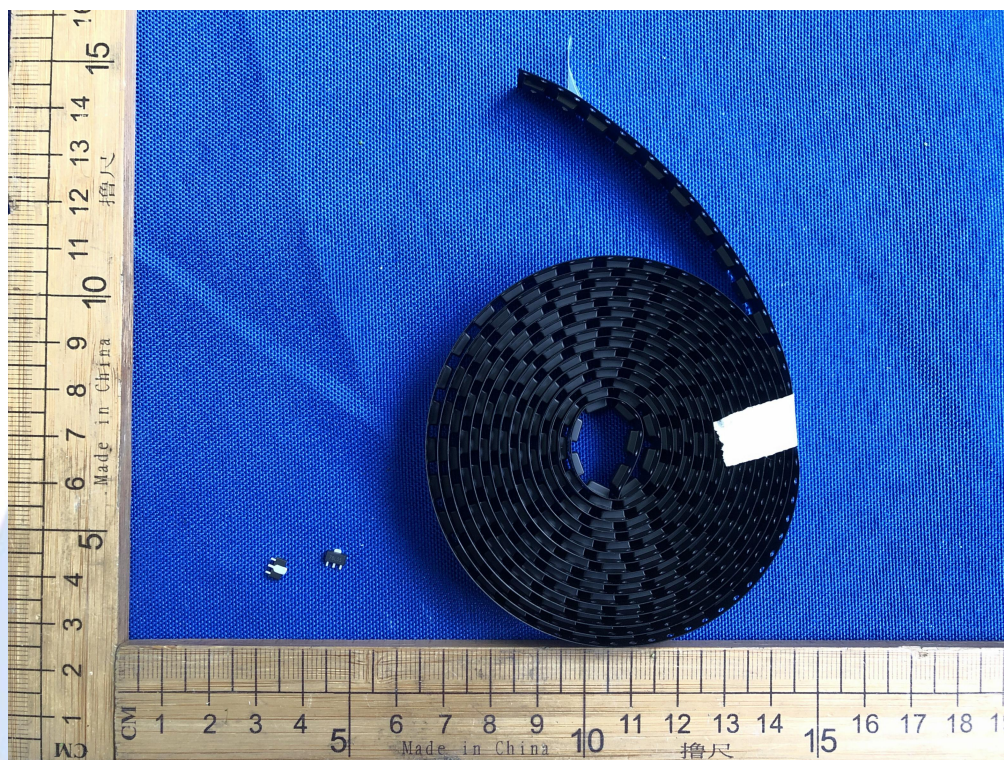
- Note:**
1. mg/kg= ppm
  2. N.D.= Not Detected(<MDL)
  3. MDL = Method Detection Limit
  4. -- = No Testing

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**Sample photo:**



\*\*\* End of Report \*\*\*

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